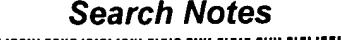


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/846,464	KIM ET AL.
	Examiner	Art Unit
	Shick C. Hom	2616

SEARCHED

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner